# **Electron Beam Evaporated Nanostructure WO<sub>3</sub> Thin Films**

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Abstract: In this study, nanostructured tungsten trioxide (WO<sub>3</sub>) thin films were deposited on glass substrates using electron beam evaporation at room temperature and subsequently annealed at different temperatures. The films were characterized by different analytical techniques such as, X-ray diffraction, scanning electron microscopy, and UV-Vis-NIR spectrophotometry. The films annealed at a higher annealing temperature of 723K, a broad peak cantered at 24.35°, which can be assigned to the monoclinic plane of WO<sub>3</sub>. The microstructure of the WO<sub>3</sub> films changed from nanoflakes to a little lime hydrangea structure upon variation of the annealing temperature. The bandgap of the films reduced from 3.29 eV to 3.15 eV from as deposited to post-annealed films.

Keywords: Thin films, Tungsten oxide, Electron beam evaporation, Nanostructure, gas sensors.

## **I. INTRODUCTION**

The development of more accurate and highly sensitive gas sensors is important in various areas of industry for monitoring, and controlling the concentration of gasses. Metal oxides thin films are promising in the gas sensor electronics industry, and the efficiency of the sensors of films is attributed to size, thickness, surface area and stability. Variety of nanostructures of metal oxides, such as ZnO, SnO<sub>2</sub>, MoO<sub>3</sub>, In<sub>2</sub>O<sub>3</sub>, and WO<sub>3</sub> have been widely used for gas sensor devices. Among these metal oxides, WO<sub>3</sub> is one of the best semiconductor materials for various applications like gas sensors, electrochromic devices, optical memory, smart windows, and catalysts due to its promising electrical and optical properties [1-2]. WO<sub>3</sub> thin films are prepared using several methods, such as sol-gel [3] electron beam evaporation [4], resistivity heating [5], sparking method [6], sputtering [7] and pulsed laser deposition [8]. In this study, electron beam evaporation was used to prepare a novel type of WO<sub>3</sub> nanostructured films and subsequently annealed at different temperatures, and studied the physical properties of the films.

#### **II. EXPERIMENTAL**

WO<sub>3</sub> pellets were used to prepare nanostructured films on glass substrates via electron beam evaporation. Pellets were prepared using high purity (99.99%) of WO<sub>3</sub> powder. The distance between the evaporation source and substrate was 7 cm. The parameters maintained during the deposition of the WO<sub>3</sub>films are listed in Table 1. The as deposited WO<sub>3</sub> films were post annealed at 473K, 673K and 723K in air.

## Characterization of WO<sub>3</sub> nanostructured films

The structural properties of the films were measured using X-ray diffractometer, and the microstructure was analyzed by scanning electron microscopy (SEM). Energy dispersive spectroscopy (EDS) was used to study the chemical composition of the films. The optical properties were examined by UV-Vis-NIR double beam spectrophotometer. The thickness of all the as deposited films turned to be about 260nm.

S. No.	Parameters
1	Accelerating Voltage = 48 kV
2	Accelerating Current = 1.3 mA
3	Base Pressure = $3.8 \times 10^{-6}$ mbar
4	<b>Deposition Pressure =1 x 10<sup>-3</sup> mbar</b>
5	Deposition Time =10 min
6	<b>Deposition Temperature = Room Temperature</b>

TABLE 1:
THE PARAMETERS MAINTAINED DURING THE DEPOSITION OF THE WO3FILMS

**III. RESULT AND DISCUSSIONS** 

#### A. Structural analysis

Fig. 1 shows the XRD images of the as deposited and annealed WO<sub>3</sub> films. The asdeposited WO<sub>3</sub> films exhibited an amorphous nature, and the amorphous nature of the WO<sub>3</sub> films did not change even after annealing at 673K. At low temperatures due to the low energy of tungsten oxide ions reaching the surface of the substrate, these low energy ions will prevent the crystallization of the films, consequently, the amorphous phase was obtained [9]. The films annealed at a higher annealing temperature of 723K, a broad peak centered at 24.35°, which can be assigned to the monoclinic plane of WO<sub>3</sub>, and showed an improvement of the crystal quality. The surface morphologies of these films are expected to be different. In the literature, Yu et al. [10] observed that the WO<sub>3-y</sub> films prepared by magnetron sputtering at room temperature are amorphous, no diffraction peaks can be observed. Whereas the annealed WO<sub>3-y</sub> film apparently shows diffraction peaks at  $2\theta=23.1^{\circ}$ , 24.4° and 34.2° which can be indexed as (002), (200) and (202) monoclinic planes, respectively.



Fig.1. XRD patterns of nanostructure WO<sub>3</sub> films.

#### B. Morphology and compositional analysis

Figs. 2(a)–(d) show SEM images of the nanostructured as deposited, and annealed WO<sub>3</sub> films. Fig. 2(a) shows that the as deposited WO<sub>3</sub> films exhibited a crack free surface, and smooth and homogenous nanoflakes were uniformly distributed on the substrate. The microstructure of the films changed when the films annealed at 473K, the nanoflakes agglomerated and their size is changed. On further increasing the annealing temperature to 673K, the surface of the films exhibited little lime hydrangea structure. The nanoflakes stacked together to form the little lime hydrangea structure. To the best of our knowledge, this was the first instance of using this technique to obtain this type of nanostructure. The films were annealed at a higher temperature of 723K, the cracks are appeared on the surface of the WO<sub>3</sub> films. Ashok et al. [11] observed that when the films were more visible at annealing temperature of 400°C, which was due to the strain imposed on the layer of film during heat treatment.



Fig.2. SEM images of nanostructure WO<sub>3</sub> films: (a) as deposited (b) annealed at 423K (c) annealed at 673K and (d) annealed at 723K. The elemental compositions of the nanostructured WO<sub>3</sub> films are determined using EDS. The nanostructures contained only W and O, and no other impurities were observed. The atomic percentage of tungsten and oxygen of as deposited films and annealed films is listed in Table 2. When the films are annealed, the atomic percentage of tungsten is increased and the oxygen percentage is decreased, consequently, oxygen vacancies are existed.

THE ATOMIC PERCENTAGE OF TUNGSTEN AND OXYGEN OF AS DEPOSITED FILMS AND ANNEALED FILMS.				
Sample	Atomic percentage of	Atomic percentage of		
	Oxygen (%)	Tungsten (%)		
As deposited	89.17	10.83		
Annealed at 673K	85.80	14.20		

TABLE 2. THE ATOMIC PERCENTAGE OF TUNGSTEN AND OXYGEN OF AS DEPOSITED FILMS AND ANNEALED FILMS.

#### C. Optical properties

The measured transmittance spectra of as deposited and annealed WO<sub>3</sub> films are shown in Fig.3. The optical properties of the WO<sub>3</sub> thin films were investigated in the wavelength range of 300 -1200 nm. The average transmittance of the films in the visible region is around 83% for the as deposited films, and it decreased to 78% after annealing at 723K. The decrease in transmittance was due to the increase in scattering light caused by the increase of surface roughness of the films, and also the higher annealing temperatures lead to the densification of the films, thus it reduces transmittance [12]. The absorption edge of the films is shifted towards the longer wavelength region as the annealing temperatures increase, as observed in transmittance spectra.



Fig.3. Optical transmittance spectrum of nanostructure WO<sub>3</sub> films.

The optical band gap ( $E_g$ ) of the films was evaluated from the extrapolation of the linear portion of the plots of  $(\alpha h v)^{1/2}$  versus (h v) ( $\alpha$  is the absorption coefficient, h v is the photon energy). Figure 4 shows the Tauc plot for nanostructure as deposited and annealed WO<sub>3</sub> films. The obtained band gap values are 3.29 eV, 3.24 eV, 3.18 eV and 3.15 eV for as deposited, 473K, 673K, and 723K annealed films, respectively. The larger band gap of the deposited thin films can be attributed to their amorphous nature. The bandgap of the films reduced from 3.29 eV to 3.15 eV from as deposited to post-annealed films. This decrease in

the band gap with annealing temperature is due to increase in the crystallinity of films and may be correlated with the formation of oxygen vacancies [13-14]. Similar behaviour was observed by Amar et al. [15] in dc magnetron sputtered WO<sub>3</sub> films, and the band gap values were reduced from 3.2 to 2.7 eV with increasing the annealing temperature from as deposited to  $600^{\circ}$ C.



Fig.4. Plot of  $(\alpha hv)^{1/2}$  vs (hv) of nanostructure WO<sub>3</sub> films.

### **IV. CONCLUSIONS**

Nanostructured WO<sub>3</sub> films were prepared using the electron beam evaporation method and studied structural, chemical and optical properties of as deposited and annealed films. The as-deposited nanostructured WO<sub>3</sub> films were amorphous in nature. The crystallinity of the films increased after annealing the films at higher temperatures. The microstructure of the WO<sub>3</sub> films was highly influenced by the annealing temperature. The microstructure of the WO<sub>3</sub> films changed from nanoflakes to a little lime hydrangea structure upon variation of the annealing temperature. The average transmittance of the films in the visible region is around 83% for the as deposited films, and it decreased to 78% after annealing at 723K. The present obtained nanostructured WO<sub>3</sub> thin films are cost-effective and very useful for gas sensor applications.

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